

SIHP240N60E-GE3-VB Datasheet

Single-N 650V TO220 SJ_Multi-EPI MOSFET

PRODUCT SUMMARY				
V _{DS} (V) at T _J max.	650			
R _{DS(on)} at 25 °C (Ω)	V _{GS} = 10 V 0.36			

FEATURES

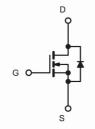
- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Q_a)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial

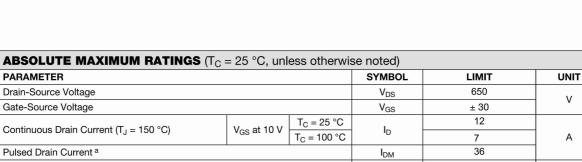






N-Channel MOSFET

Top View



Drain-Source Voltage			V_{DS}	650	V
Gate-Source Voltage			V _{GS}	± 30	\ \ \ \
Continuous Drain Current (T _{.I} = 150 °C)	V _{GS} at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	1	12	A
Continuous Drain Current (1) = 150 C)	V _{GS} at 10 V	T _C = 100 °C	ID	7	
Pulsed Drain Current ^a			I _{DM}	36	
Linear Derating Factor				1.67	W/°C
Single Pulse Avalanche Energy b			E _{AS}	830	mJ
Maximum Power Dissipation			P _D	210	W
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C
Drain-Source Voltage Slope T _J = 125 °C		dV/dt	50	V/ns	
Reverse Diode dV/dt ^d		uv/dt	15	V/IIS	
Soldering Recommendations (Peak Temperature) c for 10 s			260	°C	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD}=100$ V, starting $T_J=25~^{\circ}C,\,L=28.2$ mH, $R_g=25~\Omega,\,I_{AS}$ =6A. c. 1.6 mm from case.

PARAMETER

d. $I_{SD} \le I_D$, dI/dt = 100 A/ μ s, starting $T_J = 25$ °C.

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THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.7	G/W		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				•			
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 1 mA	650	-	-	٧
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.70	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		2.5	-	4.5	V
		$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Gate-Source Leakage	I_{GSS}		V _{GS} = ± 30 V		-	± 1	μA
		V _{DS} = 650V, V _{GS} = 0 V		-	-	1	μΑ
Zero Gate Voltage Drain Current	I _{DSS}		$V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 ^{\circ}\text{C}$		-	100	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D =4A	-	0.360	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 30 V, I _D =4A		-	5.6	-	S
Dynamic		'		1			
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	2100	-	
Output Capacitance	C _{oss}	1	$V_{DS} = 100 \text{ V},$	-	80	-	
Reverse Transfer Capacitance	C _{rss}	7	f = 1 MHz		4	-	1 !
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	62	-	pF
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	213	-	
Total Gate Charge	Qg			-	7 0	-	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_{D} = 8 \text{ A}, V_{DS} = 520 \text{ V}$		15	-	nC
Gate-Drain Charge	Q _{gd}			-	1 9	-	
Turn-On Delay Time	t _{d(on)}	V _{DD} = 520 V, I _D = 8 A,		-	18	25	
Rise Time	t _r			-	24	55	- ns
Turn-Off Delay Time	t _{d(off)}		$V_{DD} = 320 \text{ V}, I_D = 6 \text{ A},$ $V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		8 0	-	
Fall Time	t _f			-	1 2	-	
Gate Input Resistance	R_g	f = 1 MHz, open drain		-	8.0	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	12	
Pulsed Diode Forward Current	I _{SM}			-	-	36	- A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 8 A, V _{GS} = 0 V		-	-	1.5	V
Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = I _S = 8 A, dl/dt = 100 A/μs, V _R = 400 V		-	475	-	ns
Reverse Recovery Charge	Q _{rr}			-	5.8	-	μC
Reverse Recovery Current	I _{RRM}				35	_	Α

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .

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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

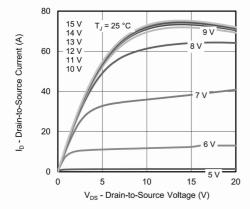
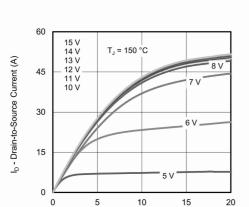


Fig. 1 - Typical Output Characteristics



 V_{DS} - Drain-to-Source Voltage (V) Fig. 2 - Typical Output Characteristics

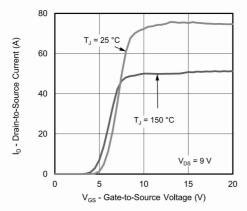


Fig. 3 - Typical Transfer Characteristics

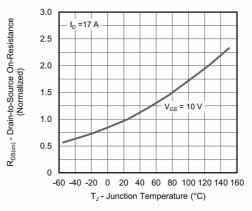


Fig. 4 - Normalized On-Resistance vs. Temperature

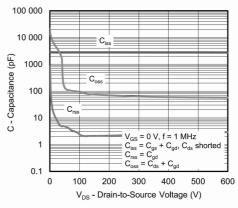


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

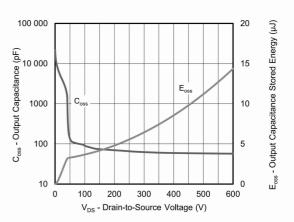


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}



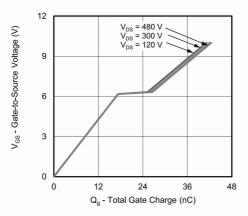


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

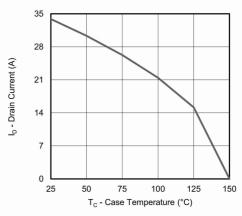


Fig. 10 - Maximum Drain Current vs. Case Temperature

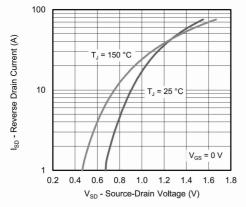


Fig. 8 - Typical Source-Drain Diode Forward Voltage

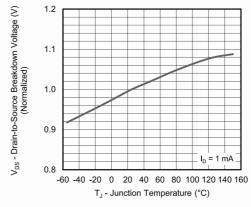


Fig. 11 - Temperature vs. Drain-to-Source Voltage

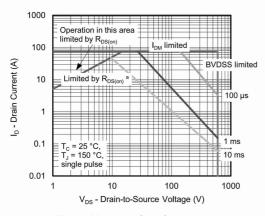


Fig. 9 - Maximum Safe Operating Area

Note

a. V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified



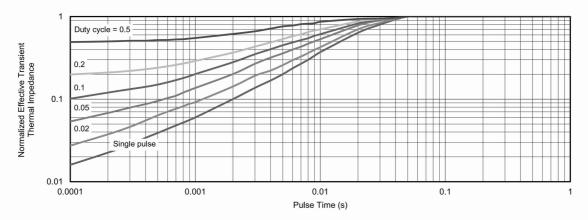


Fig. 12 - Normalized Transient Thermal Impedance, Junction-to-Case

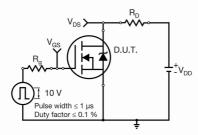


Fig. 13 - Switching Time Test Circuit

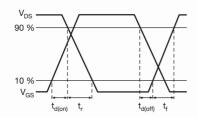


Fig. 14 - Switching Time Waveforms

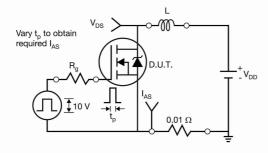


Fig. 15 - Unclamped Inductive Test Circuit

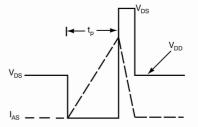


Fig. 16 - Unclamped Inductive Waveforms

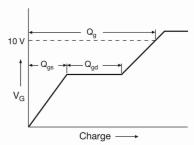


Fig. 17 - Basic Gate Charge Waveform

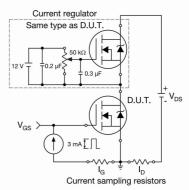
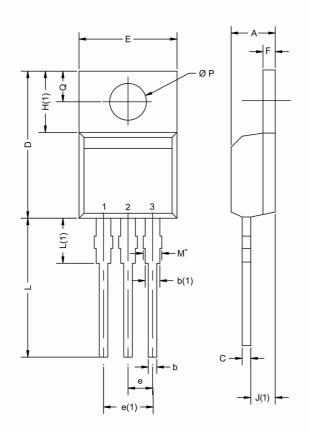


Fig. 18 - Gate Charge Test Circuit



TO-220AB



	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12					

DWG: 5471

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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